

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

First Named Inventor: Allen Gunther

Application No.: 10/053,004

Filed: 11/02/2001

For: TEST STRUCTURE AND METHOD
FOR DETERMINING A MINIMUM
TUNNEL OPENING SIZE ...

Examiner: James C Kerveros

Art Unit: 2133

Attorney Docket No.: 6557-59043

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RESPONSE TO ELECTION/RESTRICTION REQUIREMENT

Applicants respond to the Office action mailed 06/02/2004 as follows:

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Applicants respectfully traverse the election/restriction requirement on the grounds that the alleged species are not independent inventions.

Figs. 4 and 5 (species A) show and describe a basic test structure in accordance with the invention, with one write path (write path 76) for testing one tunnel opening size. Figs. 6-9 (species B) show and describe a more advanced test structure that differs from the basic structure only in the number of write paths (write paths 1 to M) to enable the testing of multiple tunnel opening sizes. (Note that Figs. 7-8 are cross-sectional views of the test structure shown in Fig. 6 and do not show a separate species C). Fig. 10 (species D) shows a test structure similar to that of Fig. 6-9, differing only in the specific structure of the tunnel opening (window).

As required by the Examiner, applicants elect the species of Figs. 6-9. Applicants believe that all claims read on this species.

Respectfully submitted,

Date: 6/24/04

By: 

Mark L. Becker
Associate General Counsel, IP
Reg. No. 31,325

Lattice Semiconductor Corporation
5555 NE Moore Ct.
Hillsboro, OR 97124
Phone: 503-268-8629
Fax: 503-268-8459
mark.becker@latticesemi.com

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